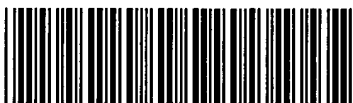


Search Notes

Application/Control No.

10/500,511

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

BADYLAK ET AL.

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated.	3/21/2007	<i>SLC</i>